Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/982,566	LUPIEN ET AL.
Examiner	Art Unit

Feben M. Haile

2663

	SEARCHED					
Class	Subclass	Date	Examiner			
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ES STRATEGY)
DATE	EXMR
1/17- 20/2006	FH
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